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TABLE OF CONTENTS

Investigating Manufacturing Defects Leading to Potential Silent Data Errors.....	1
<i>Jorge Lopez, Victor Champac</i>	
Robust DLBIST for Delay Fault Testing: Minimizing PVT Variability with Zero Temperature Coefficient (ZTC) Voltage.....	7
<i>Hanieh Jafarzadeh, Florian Klemme, Hussam Amrouch, Sybille Hellebrand, Hans-Joachim Wunderlich</i>	
Impact of Thermal Effects on Cryptographic Resilience: A Study of an ASIC Implementation of the Montgomery Ladder.....	13
<i>Ievgen Kabin, Peter Langendoerfer, Zoya Dyka</i>	
Analysis of Voltage Drop and Temperature Effects on Harmonic Errors Under EMFI on ROs.....	17
<i>Sami El Amraoui, Luc Salvo, Régis Leveugle, Paolo Maistri</i>	
Enhancing Logic Diagnosis of Field Returns Through Logic BIST in Automotive SoCs	23
<i>Paolo Bernardi, Gabriele Filippini, Giusy Iaria, Claudia Bertani, Vincenzo Tancorre</i>	
28 Nm FD-SOI 4 K RF LNA Design Using DC Transistor Characterization Measurements	29
<i>Giovani Britton, Salvador Mir, Estelle Lauga-Larroze, Benjamin Dormieu, Jose Lugo, Joao Azevedo, Sebastien Sadlo, Quentin Berlingard, Mickael Casse, Philippe Galy</i>	
Reliability-Aware Performance Optimization of DNN HW Accelerators Through Heterogeneous Quantization	35
<i>Samira Nazari, Mahdi Taheri, Ali Azarpeyvand, Mohsen Afsharchi, Christian Herglotz, Maksim Jenihhin</i>	
DOC: Detection of On-Line Failures in CNNs	41
<i>V. Turco, N. Bellarmino, A. Ruospo, R. Cantoro, E. Sanchez</i>	
Special Session: D-MATE: A Design Methodology for Connecting Automatic Test Equipment in Industry 4.0.....	47
<i>Francesco Biondani, Francesco Tosoni, Nicola Dall'Ora, Enrico Fraccaroli, Sara Vinco, Dong Seon Cheng, Franco Fummi</i>	
Late Contribution: VeriSide: A Modified Verilator for Leakage Assessment at the RTL Level	53
<i>Behnam Farnaghinejad, Antonio Porsia, Annachiara Ruospo, Alessandro Savino, Stefano Di Carlo, Ernesto Sanchez</i>	
Leveraging ATE to Optimize System-Level-Test for Multicore Automotive SoCs.....	55
<i>Francesco Angione, Paolo Bernardi, Claudia Bertani, Lorenzo Bertetto, Lorenzo Cardone, Nicola Di Gruttola Giardino, Stefano Quer, Vincenzo Tancorre</i>	
Estimating the Impact of Soft Errors on AI-Based Perception in Automotive	61
<i>Shailesh Sudhakara Hegde, Dinesh Cyril Selvaraj, Josie E. Rodriguez Condia, Nicola Amati, Carla Fabiana Chiasserini, Francesco Paolo Deflorio, Matteo Sonza Reorda</i>	
Zero-Day Hardware-Supported Malware Detection of Stack Buffer Overflow Attacks: An Application Exploiting the CV32e40p RISC-V Core.....	67
<i>Cristiano Pegoraro Chenet, Alessandro Savino, Stefano Di Carlo</i>	

Special Session: A Model-Driven Design Tool for Modelling, Simulation and Assertion-Based Verification of Hybrid Automata	73
<i>Daniele Nicoletti, Samuele Germiniani, Alessandro Aldegheri, Michele Cipriani, Davide Venturi, Tommaso Vilotto, Graziano Pravadelli</i>	
Case Study: AI-Driven Log Extraction and Trace Outlier Detection for Efficient Post-Silicon Validation	79
<i>Kowshic A. Akash, Tobias Wulf, Torsten Valentin, Alexander Geist, Ulf Kulau, John Jose, Sohan Lal</i>	
Bi-LORD: Bit-Wise Low-Cost Real Numbers Dependability Assessment in AI Applications	83
<i>Julia Azziz, Annachiara Ruospo, Ernesto Sánchez, Julio Pérez Acle</i>	
About the Functional In-Field Self-Testing of AI Accelerators	89
<i>Juan-David Guerrero-Balaguera, Josie E. Rodriguez Condia, Robert Limas Sierra, Matteo Sonza Reorda</i>	
Approximate Analytical Model Evaluating Digital Systems Compliance with Automotive Standards	95
<i>Esther Goudet, Fabio Sureau, Manan Kaila, Rémi Germe, Luis Peña Treviño, Jean-Marc Daveau, Lirida Naviner, Philippe Roche</i>	
On-Chip Aging Sensor Core for Silicon Lifecycle Management	101
<i>Fabian Vargas, Aneesh Balakrishnan</i>	
A Combined Strategy for Testing RRAMs After Manufacturing and During Lifetime	107
<i>T. S. Copetti, S. Chakraborty, L. M. Bolzani Poehls</i>	
Case Study: NASCERR: In-Mission Self-Tuning Error Correction Approach for Space Applications	113
<i>Lucas De Albuquerque, Clara Luz Salles Cavalcante, Danilo Alencar, Eléna Mallet De Chauny Druésne, João Manoel Matos Sobreira, Marcus Anderson Almeida Bezerra, Alexandre Almeida Da Silva, José Edilson Silva Filho, Jarbas Silveira, Fabian Luis Vargas</i>	
Case Study: Horizontal Side-Channel Analysis Attack Against Elliptic Curve Scalar Multiplication Accelerator Under Laser Illumination	117
<i>Dmytro Petryk, Ievgen Kabin, Peter Langendoerfer, Zoya Dyka</i>	
Improving CNN Runtime Robustness Against Soft Errors by Dropout Layer Optimization	121
<i>Robert Limas Sierra, Giuseppe Esposito, Juan-David Guerrero-Balaguera, Josie E. Rodriguez Condia, Matteo Sonza Reorda</i>	
Double Column Error Correction in RRAM Matrix Multiplication Using Weighted Checksums	127
<i>Krishnaja Kodali, Kenrick Pinto, Abhishek Das, Nur A. Toubá</i>	
Image Test Libraries for the In-Field Test of Ultra-Low-Power Devices	133
<i>Antonio Porsia, Giacomo Perlo, Annachiara Ruospo, Ernesto Sanchez</i>	
Zero Overhead Error-Tolerant Communication	139
<i>Somayeh Sadeghi Kohan, Sybille Hellebrand, Hans-Joachim Wunderlich</i>	
Case Study: UVM-FIE: Enhancing UVM-Based Fault Injection Library for Complex Designs	145
<i>Leonardo S. Tavares, Wang J. Chau, Fernando J. Fonseca</i>	
IoT-Based Digital Twin for Vehicle Battery Testing and Emissions Analysis	149
<i>George Flutur, Ovidiu-Petru Stan, Gabriel Chindris, Liviu-Cristian Miclea</i>	

Grouped Feature Selection for SMONs Placement in MCU Performance Screening.....	155
<i>Nicolò Bellarmino, Riccardo Cantoro, Martin Huch, Tobias Kilian, Giovanni Squillero</i>	
Generation of Simulated Neutrino Signals for the Digitization Subsystem in the DAPHNE Test Bench of the DUNE Experiment.....	161
<i>Valentina Rodríguez, Jerónimo López, Juan Fajardo, Valentina Restrepo, Fabian Andres Castaño</i>	
UNApprox: An Open-Source Tool for Loop Perforation in Approximate Computing.....	167
<i>Alexander Aponte-Moreno, Felipe Restrepo-Calle, Cesar Pedraza Bonilla</i>	
Large Language Models for Printed Circuit Board Test Generation	173
<i>Albin Lidbäck, Erik Larsson</i>	
IoT and Edge Computing: Applications and Reliability Implications	175
<i>Edward-W. Caro-Anzola, Giuseppe Esposito, Juan-David Guerrero-Balaguera, Andrés-F. Jiménez-López, Fabián-R. Jiménez-López, Robert Limas-Sierra, Gustavo Ramirez-Espinosa, Edoardo Giusto, Bartolomeo Montrucchio, Oscar-F. Vera-Cely, Josie E. Rodriguez Condia</i>	
Preserving and Improving Verifiability of Circuits Based on Local Transformations.....	185
<i>Rolf Drechsler</i>	
Embedded Tutorial: Integrated System Hardening Seen from a Security Point of View: Dream Or Nightmare?	187
<i>Régis Leveugle</i>	

Author Index